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\mathcal{W}	A1	3,776,233	12/1973	Schaar	\/	
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	A12	6,132,410	10/2000	Van Gompel et al.	1/	
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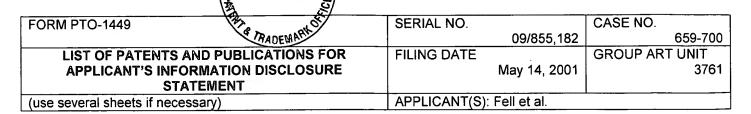
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EXAMINER		DOCUMENT	2022		CLASS/		
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m/	A14	99/49826	10/1999	WIPO			
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EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

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	B2	6,336,922 B1	1/2002	Van Gompel et al.		
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1		B6	3-205053	9/1991	Japan		Х	
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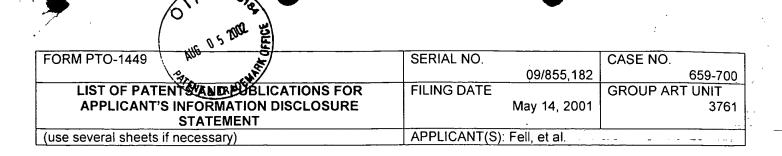
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